

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	09605293	CHAPEK, DAVID L.
	<b>Examiner</b>	<b>Art Unit</b>
	Jay C Kim	2815

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
257	288, 410, E21.423, E21.625, E21.639, E29.273, E29.309	6/5/12	J.K.

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST (US-PGPUB; USPAT; USOCR), See EAST Search History	6/5/12	J.K.

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
257	288, 410, E21.423, E21.625, E21.639, E29.273, E29.309	6/5/12	J.K.

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